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I HEREBY CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO: THE COMMISSIONER FOR PATENTS, P.O. Box 1450, Alexandria, VA 22313, On Date of Deposit: 04/18/2005.

Person Making Deposit: Robert Faber

Robert Faber

Signature

4-18-05

Date

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Rosenbluth, et al.

Application No.: 10/783,938

Filed: 02/20/2004

For: Fast Model-Based Optical Proximity Correction

)Attorney Docket No. FIS920040011US1

)Examiner: Not yet assigned

)Group Art Unit: 2873

)Date: April 18, 2005

The Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the document listed on the enclosed Form PTO-1449. The Examiner's attention is directed to the following US Publications.

FIS920040011US1

1

04/22/2005 DTESSEM1 00000083 090458 10783938

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<u>US Publications:</u>	<u>Date</u>	<u>Author</u>
"Method Of Measuring The Spatial Resolution Of A Photoresist"	2002	J.A. Hoffnagle, et al.
"Reduction Of ASIC Gate-Level Line-End Shortening By Mask Compensation"	1995	J. Garofalo, et al.
"Improved Modeling Performance Wuth An Adapted Vectorial Formulation Of The Hopkins Imaging Equation"	2003	K. Adam, et al.
" Simulation Of Imaging And Stray Light Effects In Immersion Lithography"	2003	S. Hoffman, et al.

In accordance with 37 C.F.R. § 1.98(a)(2)(iii), a copy of the listed US Publications are enclosed..

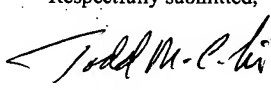
The Commissioner is authorized to charge to Deposit Account No. 09-0458 the amount to cover the fee under 37 C.F.R. § 1.17(p). Any additional fees due or overpayments should also be charged or credited to Deposit Account No. 09-0458.

CONCLUSION

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned agent may be reached by telephone at (845)894-6919. All correspondence should continue to be directed to the address listed below.

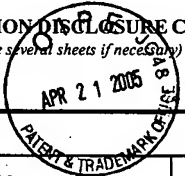
Respectfully submitted,

 4/15/2005

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INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) FIS920040011US1	Application Number 10/783,938
Applicant(s) Rosenbluth, et al.		
Filing Date 02/20/2004		Group Art Unit 2873



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
	REF.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS		<i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>
		1) "Method Of Measuring The Spatial Resolution Of A Photoresist" - J.A. Hoffnagle, et al. 2002 Optical Society of America - p. 1776 2) "Reduction Of ASIC Gate-Level Line-End Shortening By Mask Compensation" - J. Garofalo, et al. SPIE Vol. 2440 - Optical/Laser Microlithography VIII - p. 171
		3) "Improved Modeling Performance With An Adapted Vectorial Formulation Of The Hopkins Imaging Equation" - Adam, et al. - p. 78-91 4) "Simulation Of Imaging And Stray Light Effects In Immersion Lithography" - Hafeman, et al. SPIE Vol. 5040 - Optical Microlithography XVI, ed. Anthony Yen (2003), p. 700

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.